

Search Notes

Application/Control No.

10/824,967

Examiner

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Applicant(s)/Patent under
Reexamination

BAXTER ET AL

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
710	5-6,22- 25,52- 53,111- 117	11/14/2006	CS
711	147-153	11/14/2006	CS
710	316-317	11/14/2006	CS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
711	147		
710/111, 117, 5, 316			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	11/13/2006	CS
PALM for double patenting	11/14/2006	CS
EAST (uspgpub, uspat, epo, jpo, derwnet, ibmtdb, usocr, derwent)	11/14/2006	CS